

IRFP150, IRFP151, IRFP152, IRFP153

34A and 40A, 60V and 100V, 0.055 and 0.08 Ohm,
N-Channel Power MOSFETs

July 1998

Features

- 34A and 40A, 60V and 100V
- $r_{DS(ON)} = 0.055\Omega$ and 0.08Ω
- Single Pulse Avalanche Energy Rated
- SOA is Power Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Ordering Information

PART NUMBER	PACKAGE	BRAND
IRFP150	TO-247	IRFP150
IRFP151	TO-247	IRFP151
IRFP152	TO-247	IRFP152
IRFP153	TO-247	IRFP153

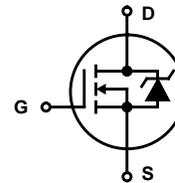
NOTE: When ordering, include the entire part number.

Description

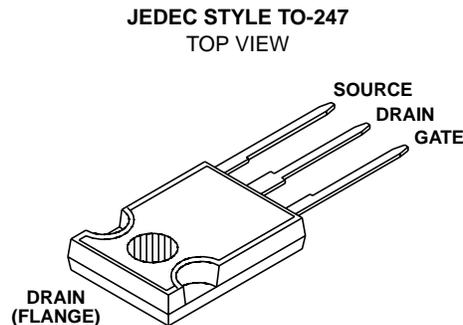
These are N-Channel enhancement mode silicon gate power field effect transistors. They are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching converters, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Formerly developmental type TA17431.

Symbol



Packaging



IRFP150, IRFP151, IRFP152, IRFP153

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$, Unless Otherwise Specified

	IRFP150	IRFP151	IRFP152	IRFP153	UNITS
Drain to Source Voltage (Note 1) V_{DS}	100	60	100	60	V
Drain to Gate Voltage ($R_{GS} = 20k\Omega$) (Note 1) V_{DGR}	100	60	100	60	V
Continuous Drain Current I_D	40	40	34	34	A
$T_C = 100^\circ\text{C}$ I_D	26	26	22	22	A
Pulsed Drain Current (Note 3) I_{DM}	160	160	140	140	A
Gate to Source Voltage V_{GS}	± 20	± 20	± 20	± 20	V
Maximum Power Dissipation P_D	180	180	180	180	W
Linear Derating Factor	1.44	1.44	1.44	1.44	$\text{W}/^\circ\text{C}$
Single Pulse Avalanche Energy Rating (Note 4) E_{AS}	150	150	150	150	mJ
Operating and Storage Temperature T_J, T_{STG}	-55 to 150	-55 to 150	-55 to 150	-55 to 150	$^\circ\text{C}$
Maximum Temperature for Soldering					
Leads at 0.063in (1.6mm) from Case for 10s T_L	300	300	300	300	$^\circ\text{C}$
Package Body for 10s, See Techbrief 334 T_{pkg}	260	260	260	260	$^\circ\text{C}$

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

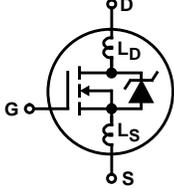
- $T_J = 25^\circ\text{C}$ to 125°C .

Electrical Specifications $T_C = 25^\circ\text{C}$, Unless Otherwise Specified

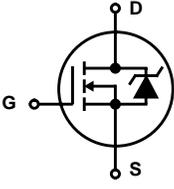
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage IRFP150, IRFP152	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu\text{A}$ (Figure 10)	100	-	-	V
			IRFP151, IRFP153	60	-	-
Gate to Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	2.0	-	4.0	V
Zero-Gate Voltage Drain Current	I_{DSS}	$V_{DS} = \text{Rated } BV_{DSS}, V_{GS} = 0V$	-	-	25	μA
		$V_{DS} = 0.8 \times \text{Rated } BV_{DSS}, V_{GS} = 0V, T_J = 125^\circ\text{C}$	-	-	250	μA
On-State Drain Current (Note 2) IRFP150, IRFP151	$I_{D(ON)}$	$V_{DS} > I_{D(ON)} \times r_{DS(ON)MAX}, V_{GS} = 10V$	40	-	-	A
			IRFP152, IRFP153	34	-	-
Gate to Source Leakage	I_{GSS}	$V_{GS} = \pm 20V$	-	-	± 100	nA
Drain to Source On Resistance (Note 2) IRFP150, IRFP151	$r_{DS(ON)}$	$V_{GS} = 10V, I_D = 22A$ (Figures 8, 9)	-	0.045	0.055	Ω
			IRFP152, IRFP153	-	0.06	0.08
Forward Transconductance (Note 2)	g_{fs}	$V_{DS} \geq 20V, I_D = 20A$ (Figure 12)	13	20	-	S
Turn-On Delay Time	$t_{D(ON)}$	$V_{DD} = 50V, I_D = 40A, R_G = 6.8\Omega, R_L = 1.2\Omega$ (Figures 17, 18) MOSFET switching times are essentially independent of operating temperature	-	15	24	ns
Rise Time	t_r		-	140	210	ns
Turn-Off Delay Time	$t_{D(OFF)}$		-	60	89	ns
Fall Time	t_f		-	90	140	ns
Total Gate Charge (Gate to Source + Gate to Drain)	$Q_{g(TOT)}$		$V_{GS} = 10V, I_D = 40A, V_{DS} = 0.8 \times \text{Rated } BV_{DSS}, I_{g(REF)} = 1.5\text{mA}$ (Figures 14, 19, 20) Gate Charge is Essentially Independent of Operating Temperature	-	70	110
Gate to Source Charge	Q_{gs}		-	20	-	nC
Gate to Drain "Miller" Charge	Q_{gd}		-	30	-	nC

IRFP150, IRFP151, IRFP152, IRFP153

Electrical Specifications $T_C = 25^\circ\text{C}$, Unless Otherwise Specified (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Input Capacitance	C_{ISS}	$V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = 1.0\text{MHz}$ (Figure 11)		-	2000	-	pF
Output Capacitance	C_{OSS}			-	1000	-	pF
Reverse-Transfer Capacitance	C_{RSS}			-	350	-	pF
Internal Drain Inductance	L_D	Measured From the Drain Lead, 6mm (0.25in) From the Package to the Center of the Die	Modified MOSFET Symbol Showing the Internal Devices Inductances 	-	5.0	-	nH
Internal Source Inductance	L_S	Measured From the Source Lead, 6mm (0.25in) from the Header to the Source Bonding Pad		-	12.5	-	nH
Junction to Case	$R_{\theta JC}$			-	-	0.70	$^\circ\text{C/W}$
Junction to Ambient	$R_{\theta JA}$	Free Air Operation		-	-	30	$^\circ\text{C/W}$

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Continuous Source to Drain Current	I_{SD}	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Diode 		-	-	40	A
Pulse Source to Drain Current (Note 3)	I_{SDM}			-	-	170	A
Source to Drain Diode Voltage (Note 2)	V_{SD}	$T_J = 25^\circ\text{C}$, $I_{SD} = 40\text{A}$, $V_{GS} = 0\text{V}$ (Figure 13)		-	-	2.5	V
Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}$, $I_{SD} = 40\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$		98	-	530	ns
Reverse Recovered Charge	Q_{RR}	$T_J = 25^\circ\text{C}$, $I_{SD} = 40\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$		0.41	-	2.5	μC

NOTES:

2. Pulse Test: Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
3. Repetitive Rating: Pulse width limited by Max junction temperature. See Transient Thermal Impedance curve (Figure 3).
4. $V_{DD} = 10\text{V}$, starting $T_J = 25^\circ\text{C}$, $L = 170\mu\text{H}$, $R_G = 50\Omega$, Peak $I_{AS} = 40\text{A}$. See Figures 15, 16.

IRFP150, IRFP151, IRFP152, IRFP153

Typical Performance Curves Unless Otherwise Specified

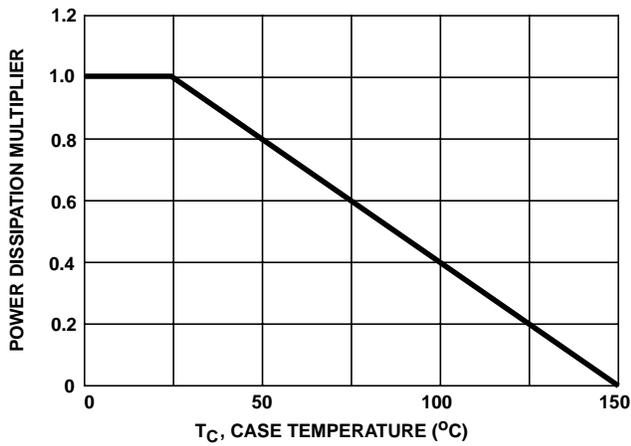


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

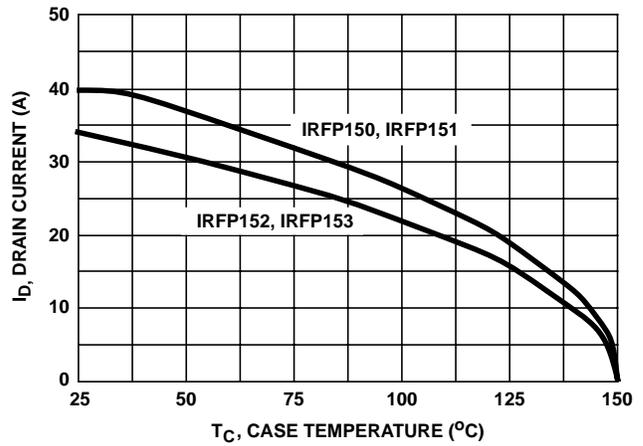


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

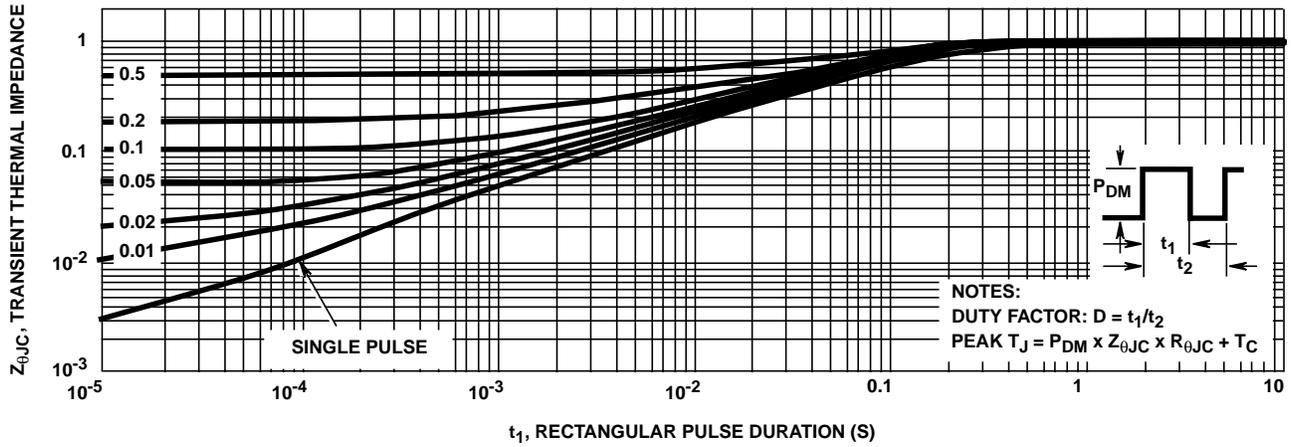


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

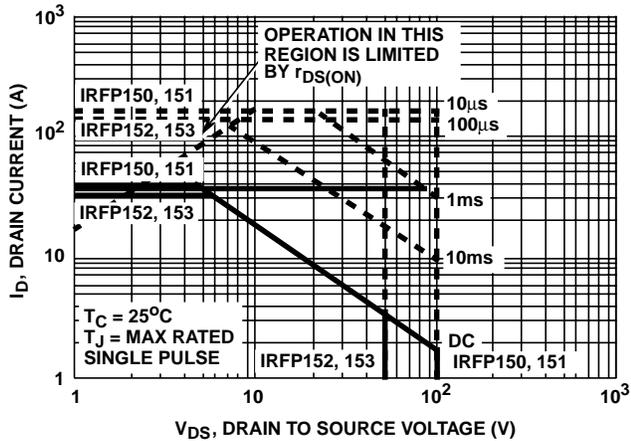


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

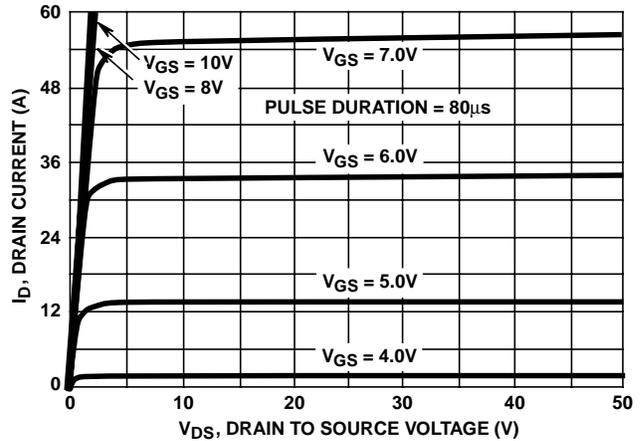


FIGURE 5. OUTPUT CHARACTERISTICS

Typical Performance Curves Unless Otherwise Specified (Continued)

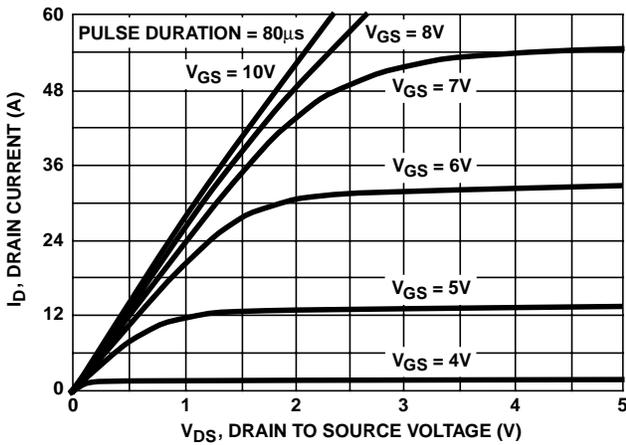


FIGURE 6. SATURATION CHARACTERISTICS

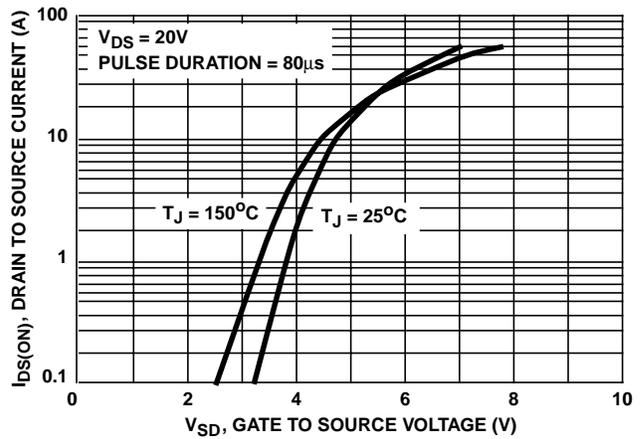


FIGURE 7. TRANSFER CHARACTERISTICS

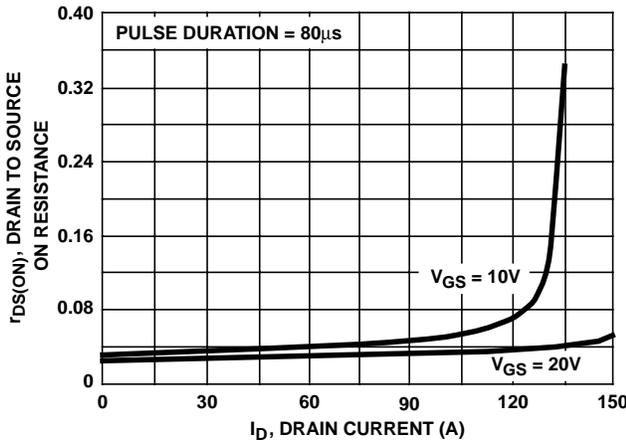


FIGURE 8. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

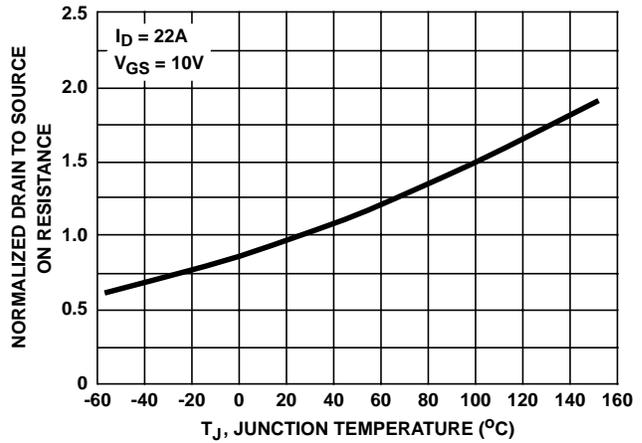


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

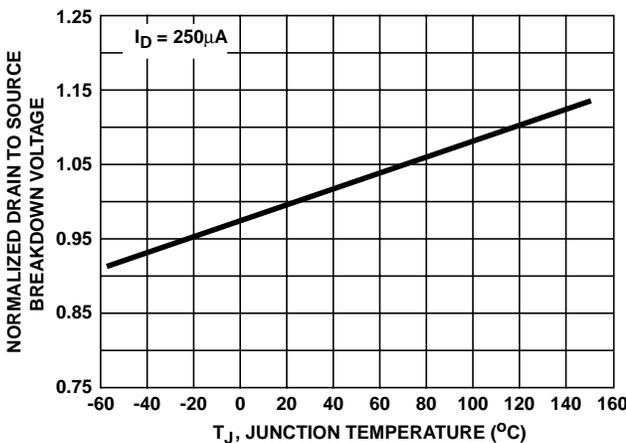


FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

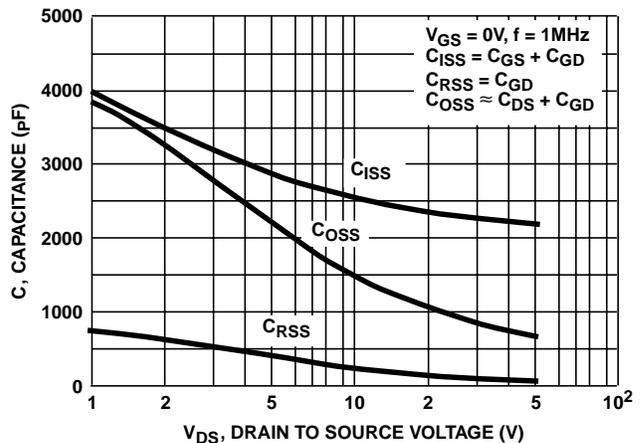


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

Typical Performance Curves Unless Otherwise Specified (Continued)

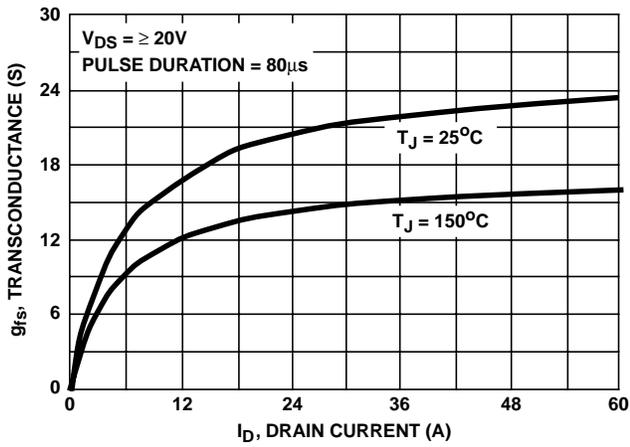


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

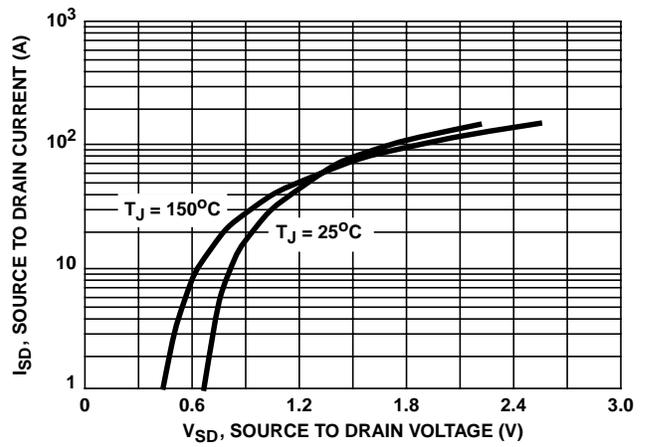


FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

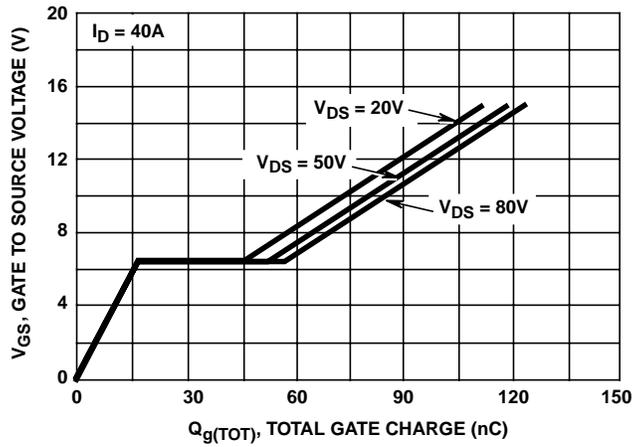


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

Test Circuits and Waveforms

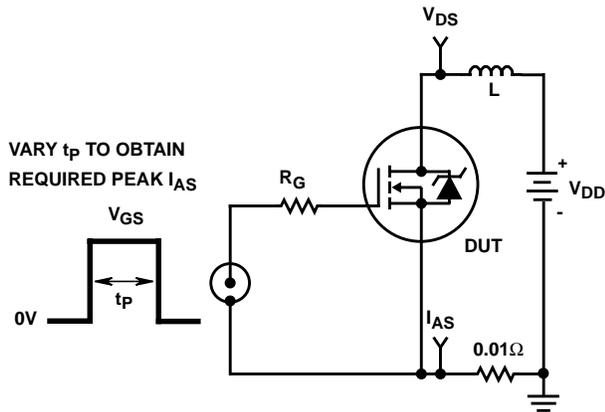


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

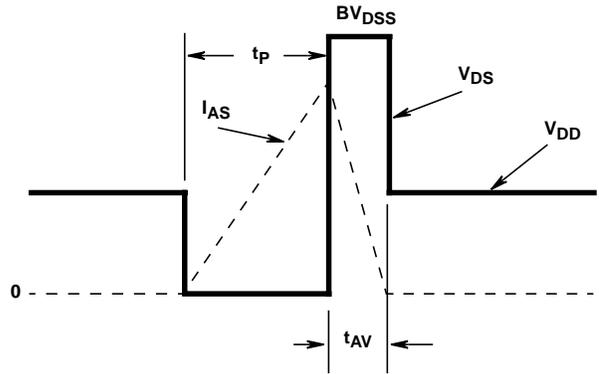


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

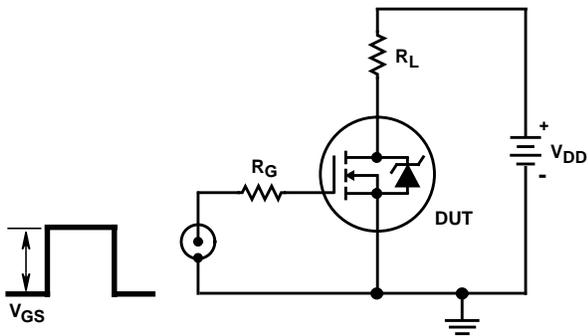


FIGURE 17. SWITCHING TIME TEST CIRCUIT

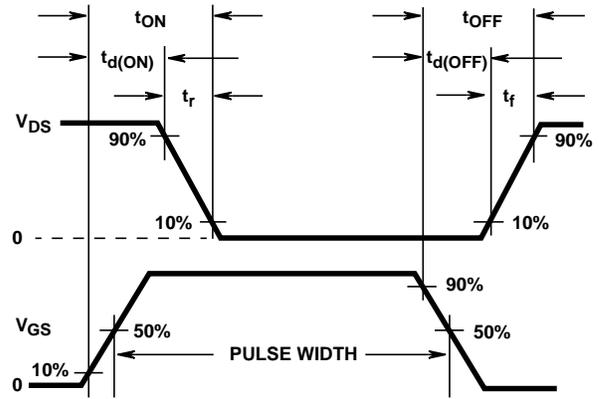


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

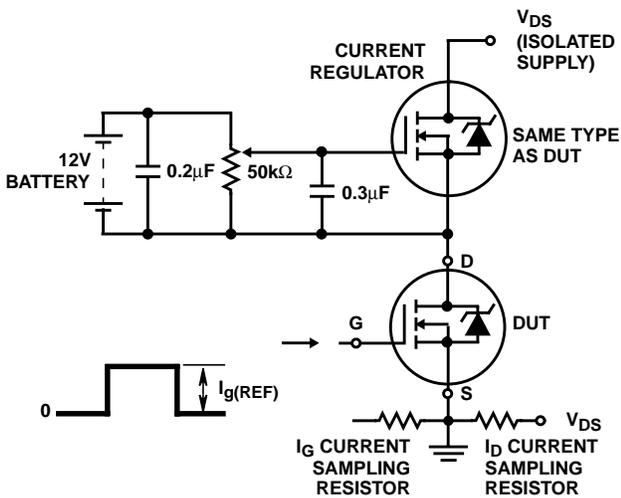


FIGURE 19. GATE CHARGE TEST CIRCUIT

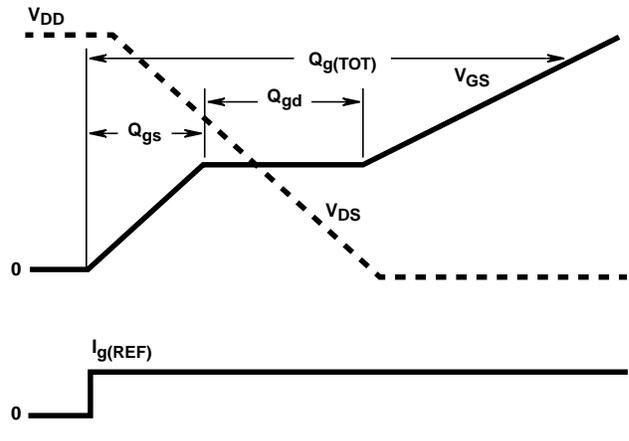


FIGURE 20. GATE CHARGE WAVEFORMS